Leveraging AI to Optimize DFT and Test Implementations

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ABSTRACT:

High quality scan test patterns that leverage advance fault models to maximize test coverage and reduce DPPM present challenges to silicon design for test. To meet these increasing challenges, AI-driven testing processes, scripting, and analysis can provide a transformative opportunity to silicon testing designs and pattern generation. This paper will discuss AI use cases and best practices to enhance DFT enablement and ATPG processes.